

INFORMATION DISCLOSURE CITATION				ATTORNEY'S DRT NO. 033022-004		DIVISIONAL APPLICATION OF No. 09/012,790	
PTO-1449				APPLICANT Yukio SHAKUDA			
				FILING DATE June 27, 2000		GROUP 2874 (expected)	
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
JD	4,890,293	12/26/89	TANEYA et al.	372	46		
JD	5,218,613	06/08/93	SERREZE	372	45		
JD	4,567,060	01/28/86	HAYAKAWA et al.	488	44		
JD	5,210,767	05/11/93	ARIMOTO et al.	372	46		
JD	4,347,611	08/1982	SCIFRES et al.	372	45		
JD	4,982,409	01/1991	KINOSHITA et al.	372	45		
JD	5,592,502	07/07/97	MATSUMOTO et al. 1197	372	45		
JD	5,619,518	04/08/97	HORIE et al.	372	45		
JD	5,578,839	11/26/96	NAKAMURA et al.	257	96		
JD	5,247,533	09/1993	OKAZAKI et al.	372	45		
JD	5,751,752	05/1998	SHAKUDA	372	45		
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
JD	477013A2	03/25/92	EUROPE			Yes	No
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
JD	Abstract of Japanese Patent Publication No. 02-129915, dated May 7, 1992, TSUNODA						
JD	Strite et al., 'Progress and Prospects for GaN and the III-V Nitride Semiconductors', THIN SOLID FILMS, Vol. 231, pp. 197-210 (no month available)						
JD	Nakamura et al., "Candela-Class High-Brightness InGaN/AlGaIn Double-Heterostructure Blue-Light-Emitting Diodes", APPLIED PHYSICS LETTERS, Vol. 64, No. 13, pp. 1687-1689						
JD	Analysis Report No. 602020, dated April 25, 1994						
JD	Unpublished Analysis Report (translation); Surface Analysis Second Group No. 602020						
JD	Japanese Journal of Applied Physics, Vol. 32, No. 1A/B, dated January 15, 1993						
JD	Applied Physics Letters, Vol. 64, No. 13, dated March 28, 1994						
JD	IEEE Journal of Quantum Electronics, Vol. QE-17, No. 9, dated September 1981						
JD	(3) Nitride Mixed Crystal (3 pages) - written agreement against Office Action for Japanese Application 06-219892 on which this application is based						
JD	Isamu Akasaki, Advanced Electronics I-1, III-V, Group of Semiconductor Compound (1994); 1 st Edition, Baifu-kan, p. 345-347						
EXAMINER: 				DATE CONSIDERED 5/2/02			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

INFORMATION DISCLOSURE CITATION

PTO-1449

ATTORNEY'S DKT NO.
033022-004DIVISIONAL APPLICATION
OF No. 09/012,790
*09/164,197*APPLICANT
Yukio SHAKUDAFILING DATE
June 27, 2000GROUP
2874 (expected)

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
<i>JD</i>	JP-A 1-217986	08/31/89	JAPAN	<i>5</i>	<i>1</i>		
<i>JD</i>	JP-A 4-87378	07/31/90	JAPAN	<i>1</i>	<i>1</i>		
<i>JD</i>	JP-A 4-127595	04/28/92	JAPAN	<i>1</i>	<i>1</i>		
<i>JD</i>	JP 1-111375	04/28/89	JAPAN	<i>1</i>	<i>1</i>		
<i>JD</i>	JP-A 6-177423	05/17/93	JAPAN	<i>1</i>	<i>1</i>		
<i>JD</i>	JP-8355	02/12/99	JAPAN	<i>1</i>	<i>1</i>		

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

~~U.S. Application No. 09/166,071, filed October 5, 1998~~

EXAMINER

DATE CONSIDERED

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